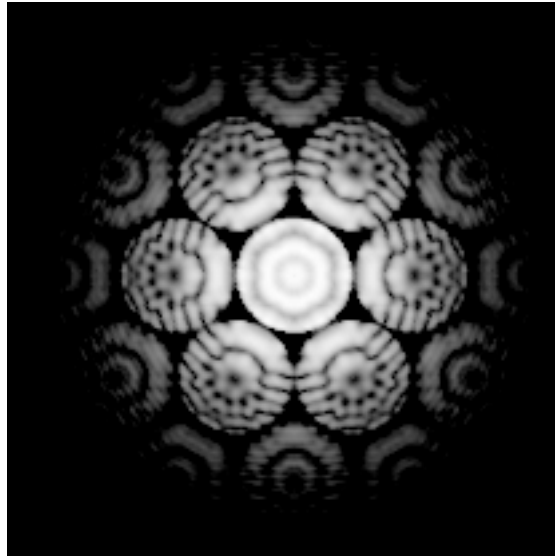


*Optional
Function*

CBED

for *MacHREM*TM / *WinHREM*TM

Coherent Convergent Beam Electron Diffraction Pattern Simulation Program



Simulated CBED pattern for Si [111]

This optional function adds the capability for simulating coherent convergent beam electron diffraction (CBED) patterns to the *MacHREM*TM / *WinHREM*TM program suite.

- User Friendly Graphical Interface Even a novice user can easily generate his/her data and perform computation.
- Reliable and Efficient Algorithm Dynamical electron interaction is efficiently estimated by using the FFT multislice technique.
- High Quality Image Output All images are generated with a standard image format of Windows/Mac OS. Therefore, high quality images can be printed from them, and they can be imported into another application.

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